

TEST REPORT

Operator:

Test site:

Instrument's data

Report created on

Type: EurotestAT

Ser.No.: 10341121

03-11-2018

Model: MI 3101

Producer: Metrel d.d.

No Results

1 DR AARHUS / OKT 2018 / E207 4POLET PASS
24.10.2018 11:08 (MORTEN ULRIK)

RCD: Tripout time PASS
t: 25.8ms
Uc: 0.2V
Idn: 300mA
type: AC₀ 
MUL.: x1
Ulim: 50V
SYS.: TN/TT

RCD: Tripout time PASS
t: 9.5ms
Uc: 0.8V
Idn: 300mA
type: A₀ 
MUL.: x1
Ulim: 50V
SYS.: TN/TT







RCD: Tripout time PASS
t: 14.6ms
Uc: 0.3V
Idn: 300mA
type: A₀^{180°} 
MUL.: x1
Ulim: 50V
SYS.: TN/TT

RCD: Tripout current PASS
I: 225.0mA
Uci: 0.1V
t: 18.1ms
Idn: 300mA
type: AC₀ 
Ulim: 50V
SYS.: TN/TT







2 DR AARHUS / OKT 2018 / E700 PASS
22.10.2018 12:11 (MORTEN ULRIK)

RCD: Tripout time PASS
t: 28.8ms
Uc: 0.4V
Idn: 30mA
type: AC₀ 
MUL.: x1
Ulim: 50V
SYS.: TN/TT







TEST REPORT

No	Results	
	RCD: Tripout time t: 12.3ms Uc: 0.0V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 19.1ms Uc: 0.4V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.1V t: 31.5ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
3	DR AARHUS / OKT 2018 / E433 23.10.2018 12:54 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 50.8ms Uc: 0.9V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 27.0mA Uci: 1.0V t: 31.3ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
4	DR AARHUS / OKT 2018 / E125U 23.10.2018 11:17 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 24.1ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 19.3ms Uc: 0.4V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 209.1ms Uc: 0.4V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 19.5mA Uci: 0.1V t: 30.6ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
5	DR AARHUS / OKT 2018 / E406 25.10.2017 09:06 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 17.2ms Uc: 0.2V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.1ms Uc: 0.2V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 28.5ms Uc: 0.6V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 24.0mA Uci: 0.0V t: 18.5ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
6	DR AARHUS / OKT 2018 / E405 22.10.2018 15:22 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 36.3ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 20.0ms Uc: 0.3V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 46.8ms Uc: 0.1V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.0V t: 33.8ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
7	DR AARHUS / OKT 2018 / E100RU 25.10.2017 08:43 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 28.4ms Uc: 1.2V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 21.0mA Uci: 0.4V t: 32.3ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
8	DR AARHUS / OKT 2018 / E108 22.10.2018 18:11 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 24.2ms Uc: 0.0V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 19.5mA Uci: 0.0V t: 36.6ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
9	DR AARHUS / OKT 2018 / E106 22.10.2018 17:40 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 19.5ms Uc: 0.4V Idn: 300mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 17.1ms Uc: 0.1V Idn: 300mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 12.2ms Uc: 0.3V Idn: 300mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 240.0mA Uci: 0.2V t: 23.5ms Idn: 300mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
10	DR AARHUS / OKT 2018 / E301 24.10.2017 14:12 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 17.6ms Uc: 0.3V Idn: 300mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.7ms Uc: 0.4V Idn: 300mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 9.4ms Uc: 1.2V Idn: 300mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 240.0mA Uci: 0.0V t: 59.5ms Idn: 300mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
11	DR AARHUS / OKT 2018 / E202 24.10.2017 14:44 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 19.9ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 17.4ms Uc: 0.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 11.9ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 18.0mA Uci: 0.3V t: 43.4ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
12	DR AARHUS / OKT 2018 / E202 22.10.2018 09:50 (MORTEN ULRİK)	PASS
	RCD: Tripout time t: 29.5ms Uc: 0.4V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 9.4ms Uc: 0.7V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.4ms Uc: 0.1V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 22.5mA Uci: 0.6V t: 37.7ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
13	DR AARHUS / OKT 2018 / E412 22.10.2018 09:52 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 22.4ms Uc: 0.6V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 17.0ms Uc: 0.0V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 11.6ms Uc: 0.1V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 21.0mA Uci: 0.1V t: 22.1ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
14	DR AARHUS / OKT 2018 / E317 24.10.2017 11:10 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 29.2ms Uc: 0.5V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 23.5ms Uc: 0.2V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 21.0ms Uc: 0.4V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.1V t: 32.4ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
15	DR AARHUS / OKT 2018 / E616 24.10.2018 12:21 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 18.4ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.1V t: 29.6ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
16	DR AARHUS / OKT 2018 / E605 24.10.2017 10:57 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 21.7ms Uc: 1.0V Idn: 300mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 285.0mA Uci: 0.1V t: 33.6ms Idn: 300mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
17	DR AARHUS / OKT 2018 / E605 24.10.2018 12:12 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 20.5ms Uc: 0.2V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.2V t: 22.7ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
18	DR AARHUS / OKT 2018 / E613 24.10.2018 11:22 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 36.9ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 27.0mA Uci: 0.2V t: 39.8ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
19	DR AARHUS / OKT 2018 / E613 24.10.2018 11:23 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 20.7ms Uc: 0.2V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 19.5mA Uci: 0.0V t: 33.4ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
20	DR AARHUS / OKT 2018 / E115 U 23.10.2017 12:07 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 35.4ms Uc: 0.3V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.2ms Uc: 0.0V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 28.6ms Uc: 0.2V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.0V t: 17.1ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
21	DR AARHUS / OKT 2018 / E105B 23.10.2017 13:24 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 25.8ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 8.5ms Uc: 0.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.6ms Uc: 0.1V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 16.5mA Uci: 0.0V t: 38.5ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
22	DR AARHUS / OKT 2018 / E105B 23.10.2017 13:25 (MORTEN ULRİK)	FAIL
	RCD: Tripout time t: 26.1ms Uc: 0.1V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 9.4ms Uc: 0.2V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.9ms Uc: 0.7V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 24.0mA Uci: 0.2V t: 8.6ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
23	DR AARHUS / OKT 2018 / E105B 23.10.2017 13:26 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 25.8ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 8.9ms Uc: 0.1V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.2ms Uc: 0.0V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 21.0mA Uci: 0.0V t: 28.1ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
24	DR AARHUS / OKT 2018 / E105B 23.10.2017 13:27 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 15.1ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 14.5ms Uc: 0.0V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 7.9ms Uc: 0.2V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 16.5mA Uci: 0.1V t: 26.7ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
25	DR AARHUS / OKT 2018 / E105B 24.10.2018 09:03 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: ____ms Uc: >99.9V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	FAIL
	RCD: Tripout time t: 14.2ms Uc: 1.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 10.2ms Uc: 1.4V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: ____mA Uci: ____V t: ____ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	FAIL
26	DR AARHUS / OKT 2018 / E105B 24.10.2018 09:05 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 25.8ms Uc: 0.2V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 8.7ms Uc: 0.7V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.3ms Uc: 0.1V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 21.0mA Uci: 0.1V t: 27.7ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
27	DR AARHUS / OKT 2018 / E105B 24.10.2018 09:06 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 25.4ms Uc: 0.7V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 10.1ms Uc: 0.9V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.9ms Uc: 0.4V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 22.5mA Uci: 0.1V t: 18.0ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
28	DR AARHUS / OKT 2018 / E105B 24.10.2018 09:07 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 25.5ms Uc: 0.4V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 8.2ms Uc: 0.7V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.6ms Uc: 0.6V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 16.5mA Uci: 0.2V t: 17.4ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
29	DR AARHUS / OKT 2018 / E105B 24.10.2018 09:08 (MORTEN ULRIK)	FAIL
	RCD: Tripout time t: 25.6ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 9.0ms Uc: 0.4V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.3ms Uc: 0.1V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 21.0mA Uci: 0.0V t: 27.7ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
30	DR AARHUS / OKT 2018 / E139R 24.10.2018 09:20 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 27.0ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 10.3ms Uc: 0.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.8ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.1V t: 19.9ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
31	DR AARHUS / OKT 2018 / E420 23.10.2018 11:59 (MORTEN ULRİK)	PASS
	RCD: Tripout time t: 36.3ms Uc: 0.5V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 19.1ms Uc: 1.2V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 52.2ms Uc: 1.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 24.0mA Uci: 0.6V t: 101.4ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
32	DR AARHUS / OKT 2018 / E420 23.10.2018 12:01 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 27.7ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 30.9ms Uc: 0.1V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 17.2ms Uc: 0.6V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.0V t: 19.8ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
33	DR AARHUS / OKT 2018 / E614 24.10.2018 11:59 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 18.5ms Uc: 0.6V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 11.8ms Uc: 0.5V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 11.6ms Uc: 0.1V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 21.0mA Uci: 0.0V t: 41.2ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
34	DR AARHUS / OKT 2018 / E609 24.10.2018 11:50 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 28.1ms Uc: 0.2V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 22.5mA Uci: 0.5V t: 20.7ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
35	DR AARHUS / OKT 2018 / E604 24.10.2018 12:29 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 37.8ms Uc: 0.1V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 16.3ms Uc: 0.1V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 49.3ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.0V t: 8.6ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
36	DR AARHUS / OKT 2018 / E311 22.10.2018 15:57 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 30.8ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 19.5mA Uci: 0.2V t: 56.3ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
37	DR AARHUS / OKT 2018 / E110RU 22.10.2018 17:56 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 22.0ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 33.5ms Uc: 0.6V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 33.7ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.1V t: 22.7ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
38	DR AARHUS / OKT 2018 / E114R 22.10.2018 18:02 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 28.4ms Uc: 0.1V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 31.4ms Uc: 0.0V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 18.7ms Uc: 0.1V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 22.5mA Uci: 0.1V t: 21.6ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
39	DR AARHUS / OKT 2018 / E143R 23.10.2018 08:44 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 16.4ms Uc: 0.1V Idn: 300mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.7ms Uc: 0.3V Idn: 300mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 9.6ms Uc: 2.4V Idn: 300mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 225.0mA Uci: 0.4V t: 29.0ms Idn: 300mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
40	DR AARHUS / OKT 2018 / E318 23.10.2018 09:44 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 25.7ms Uc: 0.7V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 8.9ms Uc: 0.5V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 14.5ms Uc: 0.6V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.9V t: 28.4ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
41	DR AARHUS / OKT 2018 / E412 23.10.2018 13:58 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 37.4ms Uc: 0.7V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 22.5mA Uci: 1.0V t: 28.2ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
42	DR AARHUS / OKT 2018 / E412 22.10.2018 11:19 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 26.2ms Uc: 0.2V Idn: 300mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout time t: 8.9ms Uc: 0.1V Idn: 300mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.3ms Uc: 0.0V Idn: 300mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 225.0mA Uci: 0.0V t: 20.1ms Idn: 300mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
43	DR AARHUS / OKT 2018 / E204 24.10.2018 10:39 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 28.5ms Uc: 0.4V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 10.9ms Uc: 0.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 15.4ms Uc: 0.1V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS







TEST REPORT

No	Results	
	RCD: Tripout current I: 24.0mA Uci: 0.0V t: 29.4ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
44	DR AARHUS / OKT 2018 / E204 24.10.2018 10:41 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 28.9ms Uc: 0.1V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 19.8ms Uc: 0.0V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 18.8ms Uc: 0.0V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 27.0mA Uci: 0.1V t: 35.2ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
45	DR AARHUS / OKT 2018 / E204 24.10.2018 10:42 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 27.0ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS

TEST REPORT

No	Results	
	RCD: Tripout time t: 13.5ms Uc: 0.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 18.0ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.0V t: 19.1ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS
46	DR AARHUS / OKT 2018 / E204 24.10.2018 10:43 (MORTEN ULRİK)	PASS
	RCD: Tripout time t: 30.1ms Uc: 0.1V Idn: 30mA type: AC ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 12.4ms Uc: 0.1V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 20.2ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS

TEST REPORT

No	Results	
	RCD: Tripout current I: 25.5mA Uci: 0.0V t: 22.4ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
47	DR AARHUS / OKT 2018 / E204 24.10.2018 10:44 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 29.1ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 12.4ms Uc: 0.1V Idn: 30mA type: A _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 17.2ms Uc: 0.1V Idn: 30mA type: A ¹⁸⁰  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 24.0mA Uci: 0.1V t: 31.9ms Idn: 30mA type: AC _v  Ulim: 50V SYS.: TN/TT	PASS
48	DR AARHUS / OKT 2018 / E204 24.10.2018 10:45 (MORTEN ULRIK)	PASS
	RCD: Tripout time t: 30.6ms Uc: 0.0V Idn: 30mA type: AC _v  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS

TEST REPORT

No	Results	
	RCD: Tripout time t: 26.3ms Uc: 0.0V Idn: 30mA type: A ₀  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout time t: 21.2ms Uc: 0.0V Idn: 30mA type: A ^{180°}  MUL.: x1 Ulim: 50V SYS.: TN/TT	PASS
	RCD: Tripout current I: 25.5mA Uci: 0.1V t: 20.4ms Idn: 30mA type: AC ₀  Ulim: 50V SYS.: TN/TT	PASS